TOSHIBA 2SA1293

TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

# 2 S A 1 2 9 3

### HIGH CURRENT SWITCHING APPLICATIONS.

• Low Collector Saturation Voltage

:  $V_{CE(sat)} = -0.4V$  (Max.) at  $I_{C} = -3A$ 

• High Speed Switching Time :  $t_{stg} = 1.0 \mu s$  (Typ.)

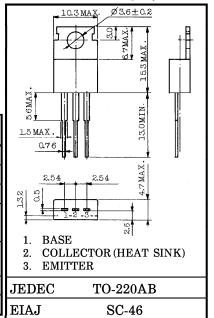
• Complementary to 2SC3258.

## MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTI	SYMBOL	RATING	UNIT		
Collector-Base Voltage	$V_{CBO}$	-100	V		
Collector-Emitter Voltage		$V_{CEO}$	-80	V	
Emitter-Base Voltage		$V_{EBO}$	<b>-7</b>	V	
Collector Current	DC	IC	<b>-</b> 5	A	
	Pulse	I <sub>CP</sub>	-8		
Collector Power Dissipation (Tc=25°C)		$P_{\mathbf{C}}$	30	w	
Junction Temperature	$T_{j}$	150	°C		
Storage Temperature Range		$T_{ m stg}$	-55~150	$^{\circ}\mathrm{C}$	
Storage Temperature Rang	T <sub>stg</sub>	-55~150	l °C		

#### INDUSTRIAL APPLICATIONS

Unit in mm



Mounting Kit No. AC75

2-10A1A

Weight: 1.9g

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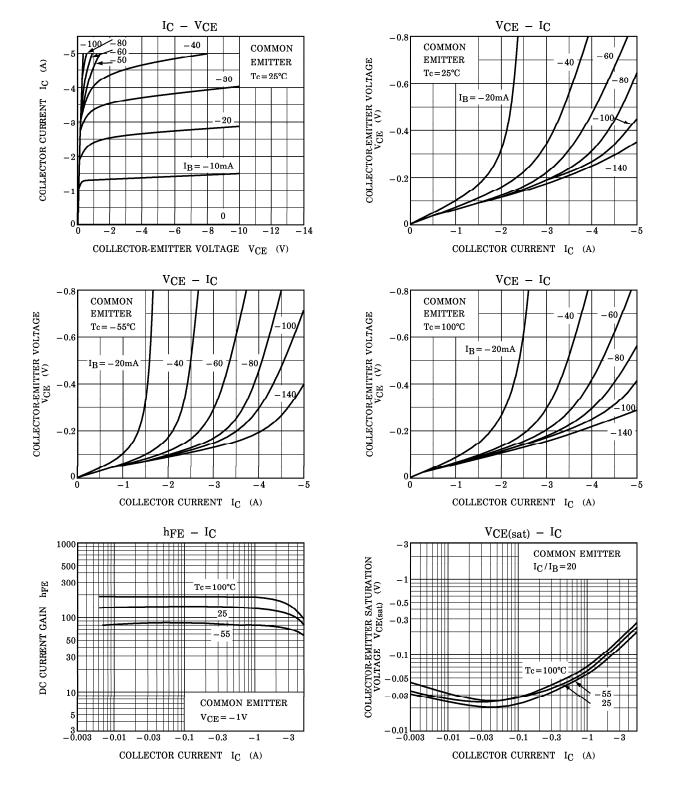
## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARA	CTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Collector Cut-off Current I(		$I_{CBO}$	$V_{CB} = -100V, I_{E} = 0$	_	_	-1	$\mu$ A	
Emitter Cut-	off Current	$I_{ m EBO}$	$V_{EB} = -7V, I_{C} = 0$	ı	_	-1	$\mu$ A	
Collector-Em Breakdown V		V <sub>(BR)CEO</sub>	$I_{C} = -10 \text{mA}, I_{B} = 0$	-80	_	_	V	
DC Current Gain		hFE(1) (Note)	$V_{CE} = -1V, I_{C} = -1A$	70	_	240		
		h <sub>FE(2)</sub>	$V_{CE} = -1V$ , $I_{C} = -3A$	30	_	_	<b> </b>	
	Collector-Emitter	V <sub>CE(sat)</sub>	$I_C = -3A$ , $I_B = -0.15A$	_	-0.2	-0.4	- V	
	Base-Emitter	V <sub>BE(sat)</sub>	$I_C = -3A, I_B = -0.15A$	ı	-0.9	-1.2		
Transition Frequency		${ m f_T}$	$V_{CE} = -4V, I_{C} = -1A$		60		MHz	
Collector Output Capacitance		$C_{ob}$	$V_{CB} = -10V, I_{E} = 0, f = 1MHz$	_	200	_	рF	
Switching Time	Turn-on Time	t <sub>on</sub>	20 \(\mu\)S INPUT \(\begin{array}{c c} \text{IB2} & OUTPUT \\ \text{OUTPUT} \\ \text{IB2} & \text{IB1} \\ \text{IB2} & \text{IB1} \\ \text{IB2} & \text{IB1} \\ \text{IB2} & \text{IB2} \\ \text{IB1} & \text{IB2} \\ \text{IB1} & \text{IB2} \\ \text{IB2} & \text{IB2} \\ \text{IB1} & \text{IB2} \\ \text{IB2} & \text{IB2} \\ \text{IB2} & \text{IB2} \\ \text{IB3} \\ \text{IB4} \\ \te	1	0.2	_		
	Storage Time	t <sub>stg</sub>			1.0	_	$\mu$ s	
	Fall Time	tf	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	1	0.1	_		

Note:  $h_{FE(1)}$  Classification  $O: 70\sim140, Y: 120\sim240$ 

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